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## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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MAY 24 2004

In re application of

Atty. Docket

RUTTEN, IVO WILHELMUS

US 018205

JOHANNES MARIE

Serial: 10/023,537

Group Art Unit: 2133

Filed: 12/18/2001

Examiner: TABONE JR, JOHN J

## MICROPROCESSOR-BASED PROBE FOR INTEGRATED CIRCUIT TESTING

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**RESPONSE UNDER 37 CFR 1.111**

Sir:

Responsive to the Office Action of 04/23/2004, please amend this application as follows: